

MOS FIELD EFFECT TRANSISTOR NP83P06PDG

SWITCHING P-CHANNEL POWER MOSFET

DESCRIPTION

The NP83P06PDG is P-channel MOS Field Effect Transistor designed for high current switching applications.

<R> ORDERING INFORMATION

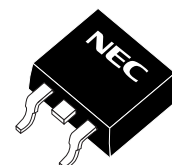
PART NUMBER	LEAD PLATING	PACKING	PACKAGE
NP83P06PDG-E1-AY ^{Note}	Pure Sn (Tin)	Tape 800 p/reel	TO-263 (MP-25ZP)
NP83P06PDG-E2-AY ^{Note}			

Note Pb-free (This product does not contain Pb in external electrode.)

FEATURES

- Super low on-state resistance
 $R_{DS(on)1} = 8.8 \text{ m}\Omega \text{ MAX. (} V_{GS} = -10 \text{ V, } I_D = -41.5 \text{ A)}$
 $R_{DS(on)2} = 12 \text{ m}\Omega \text{ MAX. (} V_{GS} = -4.5 \text{ V, } I_D = -41.5 \text{ A)}$
- High current rating: $I_{D(DC)} = \mp 83 \text{ A}$

(TO-263)



ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

Drain to Source Voltage (V _{GS} = 0 V)	V _{DSS}	-60	V
Gate to Source Voltage (V _{DS} = 0 V)	V _{GSS}	±20	V
Drain Current (DC) (T _C = 25°C)	I _{D(DC)}	±83	A
Drain Current (pulse) ^{Note1}	I _{D(pulse)}	±249	A
Total Power Dissipation (T _C = 25°C)	P _{T1}	150	W
Total Power Dissipation (T _A = 25°C)	P _{T2}	1.8	W
Channel Temperature	T _{ch}	175	°C
Storage Temperature	T _{stg}	-55 to +175	°C
Single Avalanche Current ^{Note2}	I _{AS}	49	A
Single Avalanche Energy ^{Note2}	E _{AS}	240	mJ

Notes 1. PW ≤ 10 μs, Duty Cycle ≤ 1%

2. Starting T_{ch} = 25°C, V_{DD} = -30 V, R_G = 25 Ω, V_{GS} = -20 → 0 V

THERMAL RESISTANCE

Channel to Case Thermal Resistance	R _{th(ch-C)}	1.0	°C/W
Channel to Ambient Thermal Resistance	R _{th(ch-A)}	83.3	°C/W

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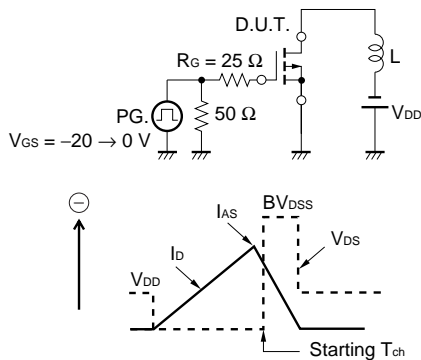
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ELECTRICAL CHARACTERISTICS (T_A = 25°C)

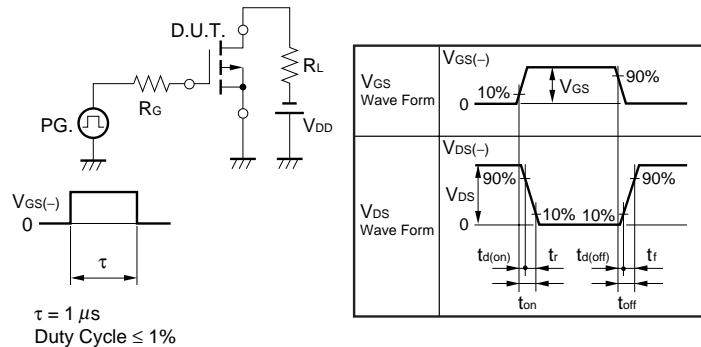
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -60 V, V _{GS} = 0 V			-10	μA
Gate Leakage Current	I _{GSS}	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = -10 V, I _D = -1 mA	-1.0	-1.6	-2.5	V
Forward Transfer Admittance ^{Note}	y _{fs}	V _{DS} = -10 V, I _D = -41.5 A	30	60		S
Drain to Source On-state Resistance ^{Note}	R _{DS(on)1}	V _{GS} = -10 V, I _D = -41.5 A		6.9	8.8	mΩ
	R _{DS(on)2}	V _{GS} = -4.5 V, I _D = -41.5 A		8.0	12	mΩ
Input Capacitance	C _{iss}	V _{DS} = -10 V,		10100		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V,		1140		pF
Reverse Transfer Capacitance	C _{rss}	f = 1 MHz		660		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = -30 V, I _D = -41.5 A,		36		ns
Rise Time	t _r	V _{GS} = -10 V,		20		ns
Turn-off Delay Time	t _{d(off)}	R _G = 0 Ω		230		ns
Fall Time	t _f			200		ns
Total Gate Charge	Q _G	V _{DD} = -48 V,		190		nC
Gate to Source Charge	Q _{GS}	V _{GS} = -10 V,		20		nC
Gate to Drain Charge	Q _{GD}	I _D = -83 A		53		nC
Body Diode Forward Voltage ^{Note}	V _{F(S-D)}	I _F = -83 A, V _{GS} = 0 V		0.94	1.5	V
Reverse Recovery Time	t _{rr}	I _F = -83 A, V _{GS} = 0 V,		63		ns
Reverse Recovery Charge	Q _{rr}	di/dt = -100 A/μs		101		nC

Note Pulsed test PW ≤ 350 μs, Duty Cycle ≤ 2%

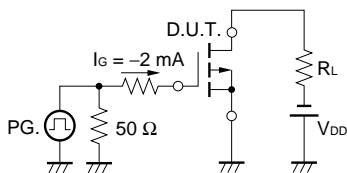
TEST CIRCUIT 1 AVALANCHE CAPABILITY



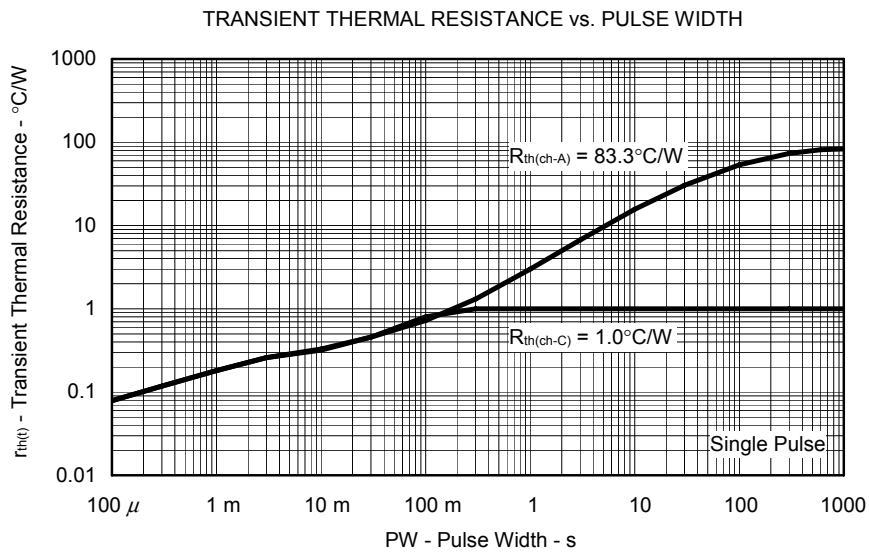
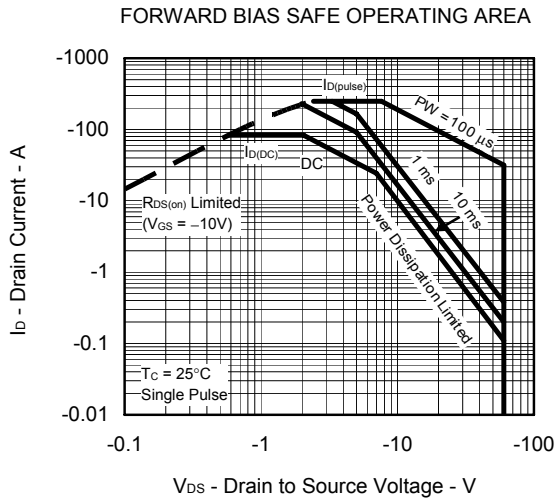
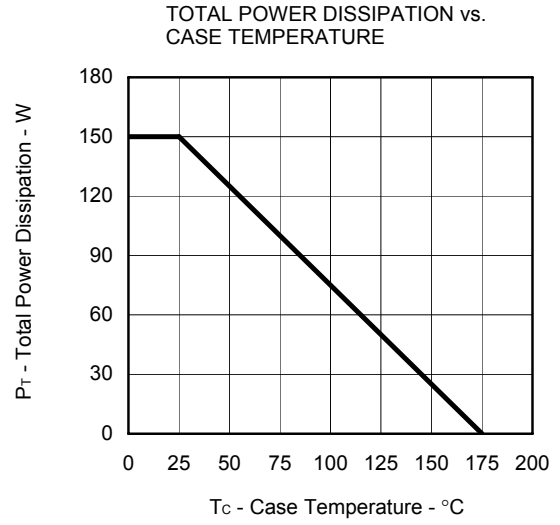
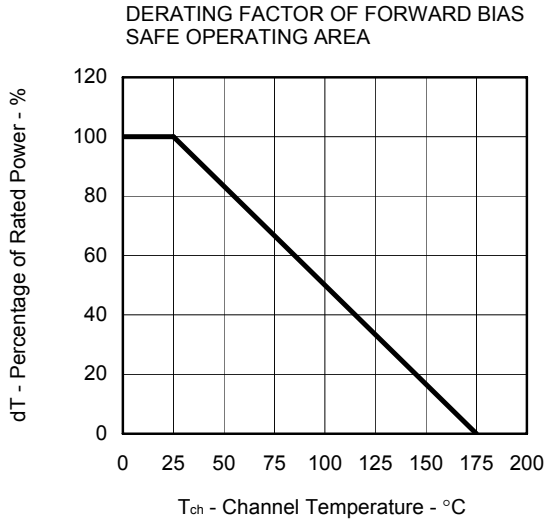
TEST CIRCUIT 2 SWITCHING TIME



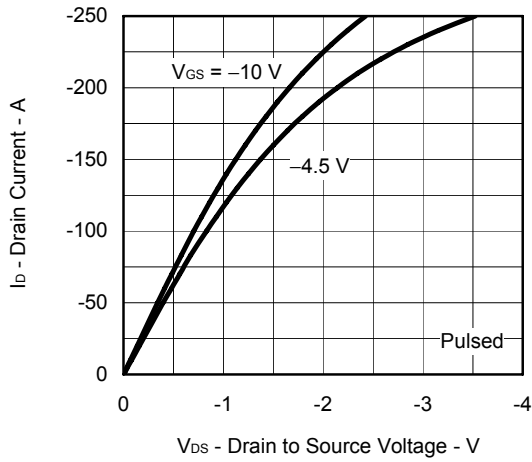
TEST CIRCUIT 3 GATE CHARGE



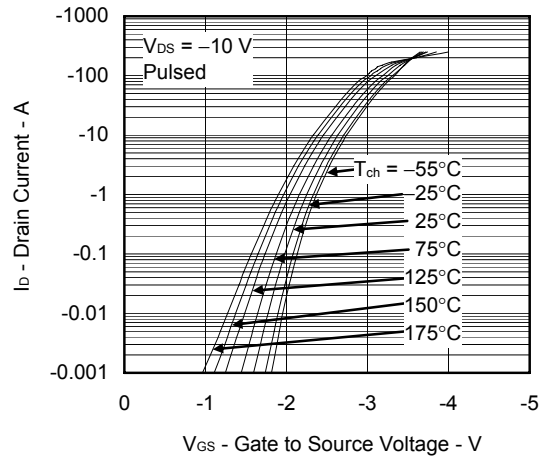
TYPICAL CHARACTERISTICS (T_A = 25°C)



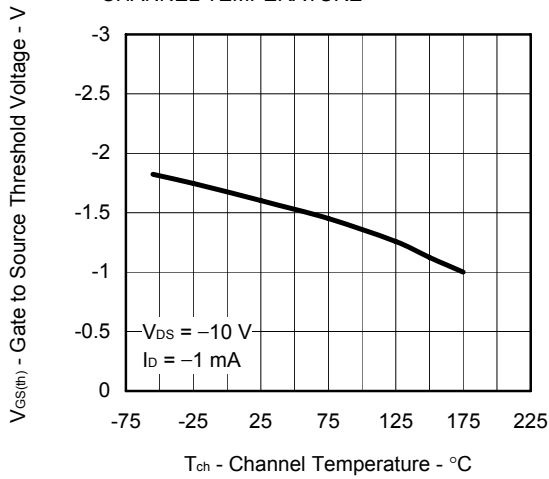
DRAIN CURRENT vs. DRAIN TO SOURCE VOLTAGE



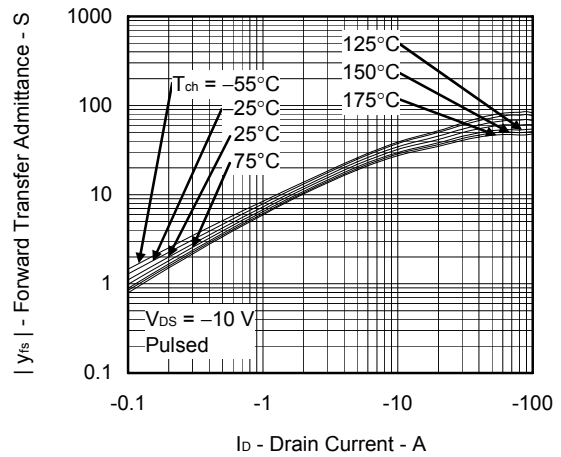
FORWARD TRANSFER CHARACTERISTICS



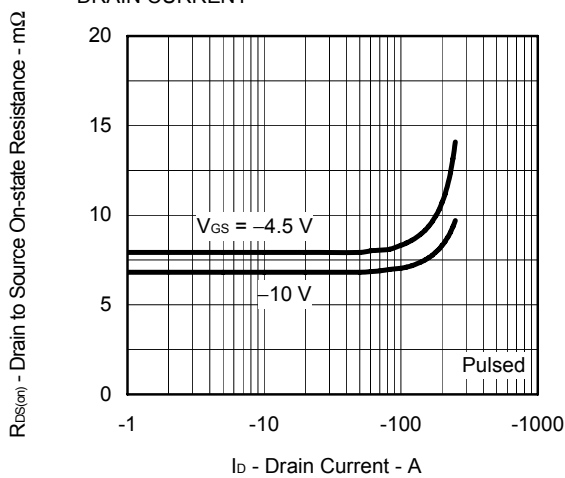
GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE



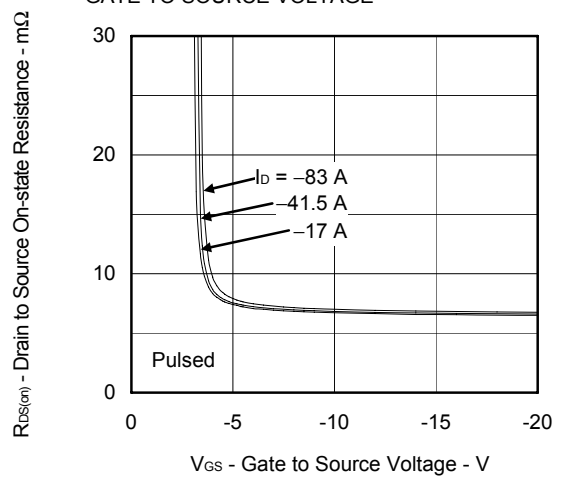
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



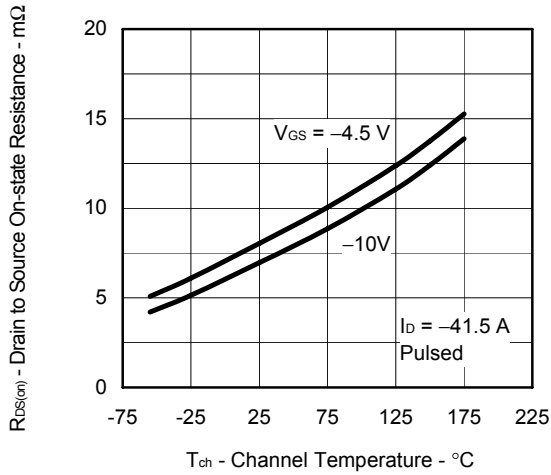
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT



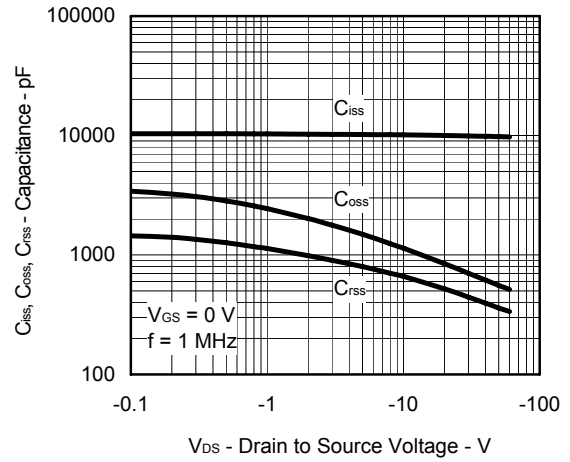
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



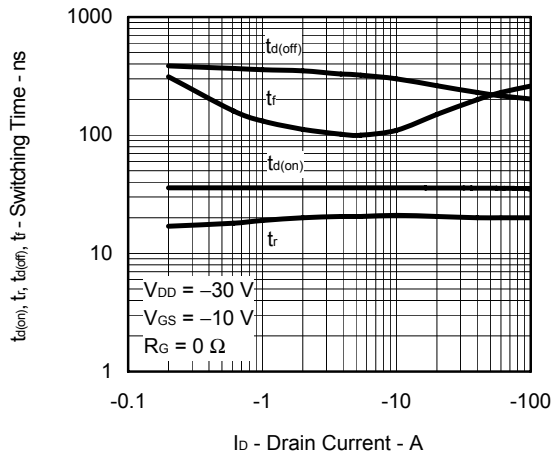
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



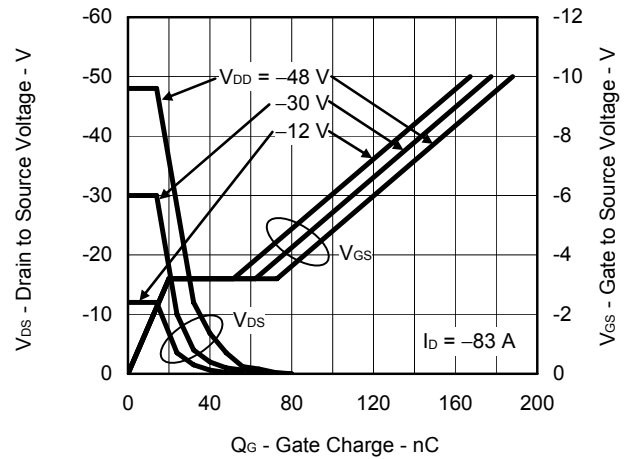
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



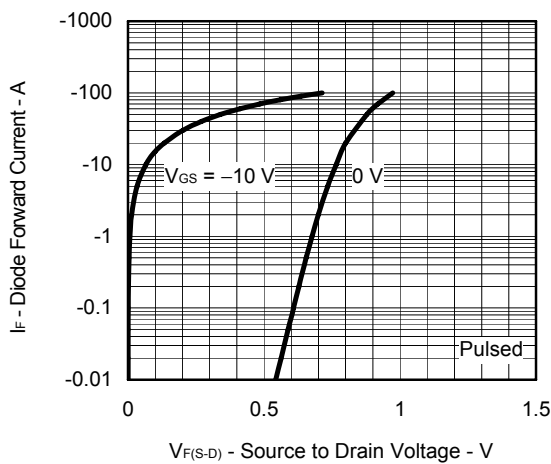
SWITCHING CHARACTERISTICS



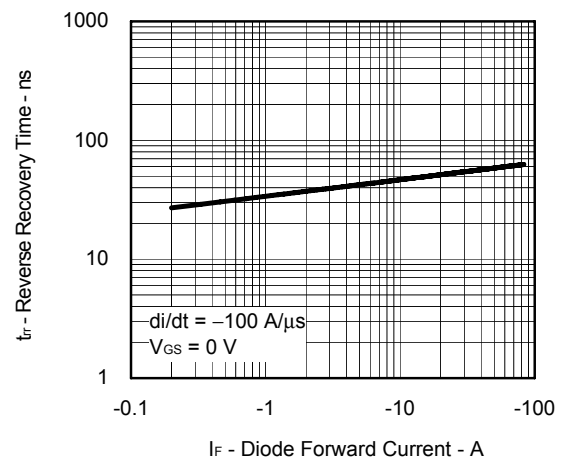
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE

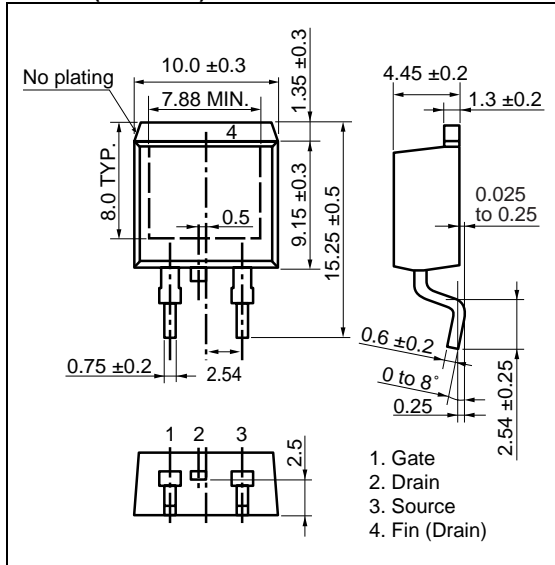


REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

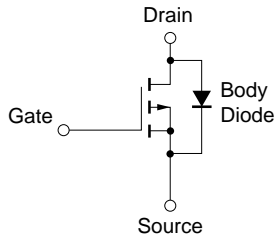


PACKAGE DRAWING (Unit: mm)

TO-263 (MP-25ZP)



EQUIVALENT CIRCUIT



Remark Strong electric field, when exposed to this device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it once, when it has occurred.

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